

RELIABILITY MONITOR

PRODUCT	MONITOR DATE	DATE CODE	ASSEMBLY FACILITY	ASSEMBLY LOT NO	PROCESS TYPE	PACKAGE TYPE
DS1267	Jul-96	9622 A1	ANAM, K.	DN603185AAA	1.2μ OX/NI	16 SOIC

STRESS/JOB NO.

READPOINT

(Sample Size/No. of Fails)

Preconditioning (P/C):
HTC Vapor Phase
P-17814

<u>Electrical</u>	<u>Cum %</u>
233/0	0.0%

Sonoscan
P-17837

<u>Post Vapor Phase</u>
2/0

Infant / High Voltage Life 125°C, -4.0 & +6.0 V P-17838, P-17941	<u>48 Hr</u>	<u>336 Hr</u>	<u>1K Hr</u>	<u>*Failure Rate</u>
	231/0	77/0	77/0	82 Fits

*Chi Squared Method, 60% C. L., 55°C & 5.5V; Temperature Derating: Ea = 0.7 ev; Voltage Derating B = 1.0

Temp Cycle -55°C to +125°C P-17942	<u>300 ~</u>	<u>1K ~</u>	<u>Cum %</u>
	39/0	39/0	0.0%

Biased Moisture 85°C/85% RH, 5.5 V. P-17943	<u>274 Hr</u>	<u>959 Hr</u>	<u>Cum %</u>
	77/0	77/0	0.0%

Autoclave 121°C/100% RH, 2 Atmos P-17944	<u>168 Hr</u>	<u>Cum %</u>
	38/0	0.0%

Failure Mode

Failure Analysis